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CumdtB
TY930-97

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Brian S. Beaman et al.

Date: September 12, 1997

Serial No.: 08/756,830

Group Art Unit: 2213

Filed: November 20, 1996

Examiner: V. Nguyen

For: A HIGH DENSITY INTEGRAL TEST PROBE AND FABRICATION METHOD

The Commissioner of Patents and Trademarks
Washington, D.C. 20231

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GROUP 2200

AMENDMENT

Sir:

In response to the Office Action dated March 12, 1996, please consider the following:

IN THE CLAIMS

Cancel claims 1 and 24 - 35.

In claims 2 and 3 cancel "1"; replace therefor ~~1~~.

4. (Amended) An apparatus for electrically testing a work piece having a plurality of electrically conductive contact locations thereon comprising:

a substrate having a first surface and a second surface;